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| | | | | | Filing Date | | | January 7, 2002 | | | | |
| STATEMENT BY APPLICANT (use as many sheets as necessary) | | | | | | First Named Inventor | | | Takenobu KISHIDA | | | |
| | | | | | | Group Art Unit | | | | 70/ | | |
| | | | | | | Examiner Name | | | | | Ž O | |
| Sheet | | 1 of I | | | | Attorney Docket Number | | 740819- | 710 | JCB68 U | | |
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¹ Unique citation designation number. ² See attached Kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). 4 For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. Skind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

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